

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/618,228	SHARMA, BALGOVIND K.	
	Examiner	Art Unit	Page 1 of 1
	Binh X. Tran	1765	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Micelle; http://www.answers.com/topic/micelle , pages 1-2
	V	low-k dielectric; http://www.semiconductorglossary.com/default.asp?SearchedField=Yes&SearchTerm=low-k ; page 1.
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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